Abstracts

S-parameter broadband measurements on-coplanar and fast extraction of the substrate intrinsic properties

J. Hinojosa. "S-parameter broadband measurements on-coplanar and fast extraction of the substrate intrinsic properties." 2001 Microwave and Wireless Components Letters 11.2 (Feb. 2001 [MWCL]): 80-82.

A broadband technique for determining the electromagnetic properties of isotropic thin-film materials, which uses a coplanar line, is presented. Complex permittivity and permeability are computed from S-parameter measurements of a coplanar cell propagating the dominant mode. Measured /spl epsi//sub /spl tau// and /spl mu//sub /spl tau// data for several materials are presented between 0.05 GHz and 40 GHz. This technique shows a good agreement between measured and predicted data.

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